



Test Report : SCW20W8-03

20W DIP Package 8:1 Ultra-Wide Input DC-DC Regulated Converter

■ DESIGN VERIFY TEST

Output Function Test

Input Function Test

Protection Function Test

■ SAFETY TEST

Safety test

■ RELIABILITY TEST

Environment Test

■ DESIGN VERIFY TEST

OUTPUT FUNCTION TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT	VERDICT
1	VOLTAGE ACCURACY	-2.0% ~ +2.0%	I/P:24VDC O/P:FULL LOAD Ta:25°C	-0.26%	P
2	RIPPLE & NOISE	100 mVp-p	I/P:24VDC O/P:FULL LOAD Ta:25°C	18 mV	P
3	LINE REGULATION	-0.5% ~ +0.5%	I/P:9VDC~75VDC O/P:FULL LOAD Ta:25°C	+0.00% ~ +0.00%	P
4	LOAD REGULATION	-1.0% ~ +1.0%	I/P:24VDC O/P:0% LOAD~FULL LOAD Ta:25°C	-0.81% ~ +0.81%	P

INPUT FUNCTION TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT	VERDICT
1	EFFICIENCY	83%	I/P:24VDC O/P:FULL LOAD Ta:25°C	83.79%	P
2	DC CURRENT	655 mA / FULL LOAD 10 mA / NO LOAD	I/P:24VDC O/P:NO / FULL LOAD Ta:25°C	652 mA / FULL LOAD 1.68 mA / NO LOAD	P

PROTECTION FUNCTION TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT	VERDICT
1	SHORT PROTECTION	CONTINUOUS	I/P:75VDC O/P:FULL LOAD Ta:25°C	CONTINUOUS, AUTOMATIC RECOVERY	P
2	OVER LOAD PROTECTION	110~190%	I/P:24VDC O/P:TESTING Ta:25°C	158.0% HICCUP MODE AUTO-RECOVER	P
3	CASE TEMPERATURE	+110°C max	I/P:24VDC O/P:TESTING Ta: TESTING	OK AUTOMATIC RECOVERY	P
4	OVER VOLTAGE PROTECTION	YES	I/P: 24VDC O/P: MIN LOAD Ta:25°C	PROTECTION TYPE : CLAMP BY TVS DIODE	P
5	UNDER VOLTAGE LOCKOUT	START-UP 8.8V(Type) SHUTDOWN OLTAGE 8.0V(Type)	I/P:TESTING O/P:FULL LOAD Ta:25°C	8.60 VDC 7.35 VDC	P

CONTROL FUNCTION TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT	VERDICT
1	REMOTE CONTROL	POWER ON : R.C. ~ -VIN >2.5~30VDC OR OPEN CIRCUIT POWER OFF : R.C. ~ -VIN <1VDC OR SHORT	I/P:24VDC O/P:100% LOAD Ta:25°C	POWER ON : R.C>1.97VDC OR OPEN POWER OFF : R.C.<1.52VDC OR SHORT	P

SAFETY TEST

SAFETY TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT	VERDICT
1	WITHSTAND VOLTAGE	I/P-O/P:3000 VDC/min	I/P-O/P:3000 VDC/min Ta:25°C	I/P-O/P: 0.002mA NO DAMAGE	P
2	ISOLATION RESISTANCE	I/P-O/P:500VDC>1000MΩ	I/P-O/P:500 VDC Ta:25°C	I/P-O/P>1000MΩ NO DAMAGE	P

RELIABILITY TEST

ENVIRONMENT TEST

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT										
1	TEMPERATURE RISE TEST	1. ROOM AMBIENT BURN-IN : 4HRS I/P:24VDC O/P:FULL LOAD Ta=25°C 2. HIGH AMBIENT BURN-IN : 4HRS I/P:24VDC O/P:FULL LOAD Ta=50°C 3. HIGH AMBIENT BURN-IN : 4HRS I/P:24VDC O/P:50% LOAD Ta=80°C	<table border="1"> <tr> <th>NO</th><th>Position</th><th>1</th><th>2</th><th>3</th></tr> <tr> <td>1</td><td>CASE</td><td>66.7°C</td><td>91.7°C</td><td>98.0°C</td></tr> </table>	NO	Position	1	2	3	1	CASE	66.7°C	91.7°C	98.0°C	
NO	Position	1	2	3										
1	CASE	66.7°C	91.7°C	98.0°C										
2	LOW TEMPERATURE TURN ON TEST	TURN ON AFTER 4 HOURS	I/P:24VDC O/P: FULL LOAD Ta= -40°C	TEST : OK										

OTHER

NO	TEST ITEM	SPECICATION	TEST CONDITION	RESULT
1	MTBF	MIL-HDBK-217F,GB,25°C TOTAL FAILURE RATE : 1.72443 M.T.B.F : >570KHRS		

TEST RESULT	TESTER	APPROVAL
PASS	ARCHEN HSIAO	PETER CHENG